

## **Quarterly Reliability Monitoring Results**

## Quarters: Q3/2021 to Q4/2022

Based on structural similarity

| Supplier Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test |  | User Part Number   |                                   |           |            |           |  |  |
|--|--|--|-----------------------------------|-----------|------------|-----------|--|--|
|  |  | PESD2CANFD27VQB-Q  |                                   |           |            |           |  |  |
|  |  | Part Description   |                                   |           |            |           |  |  |
|  |  | Nexperia DHAM  | olar                              |           |            |           |  |  |
|  |  | MCD package  |                                   |           |            |           |  |  |
|  |  | Test Conditions  | Duration                          | # Lots    | # Quantity | # Rejects |  |  |
|  | TEST Pre- and Post-Stress                                      |  |                                   |           |            |           |  |  |
| # E1   | Electrical Test  | Tamb = 25 °C   | N/A                               | see below | all parts  | see below |  |  |
| # A1   | <b>PC</b> Preconditioning                                      | JESD22-A113 Bake Tamb = 125 °C Soak Tamb = 85 °C, RH = 85% Reflow soldering                            | 24 hours<br>168 hours<br>3 cycles | 211       | 12520      | 0         |  |  |
| # B1   | HTRB<br>High Temperature Reverse<br>Bias                       | MIL-STD-750-1<br>M1038 Method A<br>Tj = Tjmax, Vr = 100% of max. datasheet<br>reverse voltage          | 1000 hours                        | 34        | 2000       | 0         |  |  |
| <b>4</b> 0.4   | TC Temperature Cycling   | JESD22-A104 -65 °C to Timax, not to exceed 150°C   | 1000 eveles                       | 78        | 4640       | 0         |  |  |
| # A4   | remperature cycling  | -03 C to filliax, flot to exceed 130 C   | 1000 cycles                       | 78        | 4640       | 0         |  |  |
| # A3 <b>or</b>   | UHAST<br>Unbiased HAST   | JESD22-A118<br>Tamb = 130 °C, RH = 85 %  | — 96 hours                        | 57        | 3420       | 0         |  |  |
| # A3 alt   | <b>AC</b><br>Autoclave   | JESD22-A102<br>Tamb = 121 °C, RH = 100 %<br>Pressure = 205 kPa (29.7 psia)                             |                                   |           |            |           |  |  |
| # A2 alt   | <b>H3TRB</b><br>High Humidity High<br>Temperature Reverse Bias | JESD22-A101<br>Tamb = 85 °C, RH = 85%, VR = 80 % of rated reverse voltage <sup>[1]</sup>               | 1000 hours                        | 75        | 4460       | 0         |  |  |
| # A5   | IOL Intermittent Operating Life                                | MIL-STD-750 Method 1037<br>ton = toff, devices powered to insure $\Delta Tj$ = 100 °C for 15000 cycles | 1000 hours                        | n.a.      | n.a.       | n.a.      |  |  |
| # A3   | E  | 222 232 2500 27000   | 1000 1100/5                       | 11.0.     | 11.a.      | 11.0.     |  |  |
| # C8   | <b>RSH</b><br>Resistance to Solder Heat                        | JESD22-A111<br>260 °C ± 5 °C   | 10 s                              | n.a.      | n.a.       | n.a.      |  |  |
| # C10  | <b>SD</b><br>Solderability                                     | J-STD-002  |                                   | 111       | 1110       | 0         |  |  |
|  |  |  |                                   |           |            |           |  |  |

<sup>[1]</sup> The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

| Wafer Fab | Technology         | Quantity | Rejects | Failure Rate (FIT) | MTTF (hrs) |
|-----------|--------------------|----------|---------|--------------------|------------|
| Nexperia  |                    |          |         |                    |            |
| DHAM      | Protection Bipolar | 2000     | 0       | 2,12               | 4,71E+08   |

<sup>© 2023</sup> Nexperia B.V.

All information hereunder is per Nexperia's best knowledge. This document does not provide for any representation or warranty express or implied by Nexperia. In case Nexperia has tested the product, this documentation reflects the outcome of the analysis of the actually tested parts only.

nexperia.com